

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1.-6. (Cancelled.)

7. (currently amended) A process for underfilling an integrated circuit that is mounted to a substrate, comprising:

dispensing a first material ~~acting as to form an~~ underfill which becomes attached to the integrated circuit and the substrate; and,

dispensing a second material ~~acting as to form~~ a circumferential fillet, the second material being different than the first material and having a lower adhesive property than the first material and becoming attached to the integrated circuit and the substrate.

8. (previously presented) The process as recited in claim 7, wherein the first material flows between the integrated circuit and the substrate.

9. (previously presented) The process as recited in claim 8, wherein the substrate moves within an oven while the first material flows between the integrated circuit and the substrate.

10. (previously presented) The process as recited in claim 7, wherein the second material is dispensed in a pattern which surrounds the first material.

11. (currently amended) A process for underfilling an integrated circuit that is mounted to a substrate comprising:

heating the substrate before a first material is dispensed;

dispensing the first material ~~acting as~~ to form an underfill, the first material becoming attached to the integrated circuit and the substrate; and,

dispensing a second material ~~acting as~~ to form a circumferential fillet, the second material being different than the first material and having a lower ~~adhesion~~ adhesive property than the first material and becoming attached to the integrated circuit and the substrate.

12. (previously presented) The process as recited in claim 11, further comprising heating the first material to a gel state.

13. (currently amended) The process as recited in claim 12, wherein the substrate is heated to a temperature that is greater than a temperature for heating said first material to said ~~partially~~ gel state.

14. (previously presented) The process as recited in claim 11, further comprising mounting the integrated circuit to the substrate with a solder bump before the first material is dispensed.

15.-30. (Cancelled.)

31. (currently amended) A process for underfilling an integrated circuit that is mounted to a substrate comprising:

heating the substrate before a first material is dispensed;

dispensing the first material ~~acting as~~ to form an underfill, the first material becoming attached to the integrated circuit and the substrate; and,

dispensing a second material ~~only~~ around a periphery of the integrated circuit to ~~acting as~~ form a circumferential fillet, the second material being different than the first material and having a lower adhesion property than the first material and becoming attached to the integrated circuit and the substrate.

32. (previously presented) The process as recited in claim 31, further comprising heating the first material to a gel state.

33. (currently amended) The process as recited in claim 32, wherein the substrate is heated to a temperature that is greater than a temperature for heating the first material to a partially gel state.

34. (previously presented) The process as recited in claim 33, wherein the first material is heated to a temperature ranging between 120 degrees Celsius to 145 degrees Celsius.

35. (currently amended) The process as recited in claim 31, wherein the dispensing of the second material is at a temperature ~~ranging~~ ranging between 80 degrees Celsius and 120 degrees Celsius.